

DOCKET NO: 247185US2SRD

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :
HIDEO TSUCHIYA, ET AL. : EXAMINER: NGUYEN, SANG H.
SERIAL NO: 10/743,830 :
FILED: DECEMBER 24, 2003 : GROUP ART UNIT: 2886
FOR: PATTERN INSPECTING METHOD :
AND PATTERN INSPECTING
APPARATUS

AMENDMENT UNDER 37 C.F.R. § 1.111

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated July 3, 2007, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Amendments to the Drawings begin on page 7 of this paper and include an attached replacement sheet.

Remarks/Arguments begin on page 8 of this paper.